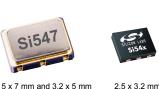


# Ultra Series<sup>™</sup> Crystal Oscillator Si547 Data Sheet

### Ultra Low Jitter Quad Any-Frequency XO (80 fs), 0.2 to 1500 MHz

The Si547 Ultra Series<sup>™</sup> oscillator utilizes Silicon Laboratories' advanced 4<sup>th</sup> generation DSPLL<sup>®</sup> technology to provide an ultra-low jitter, low phase noise clock at four selectable frequencies. The device is factory-programmed to provide any four selectable frequencies from 0.2 to 1500 MHz with <1 ppb resolution and maintains exceptionally low jitter for both integer and fractional frequencies across its operating range. The Si547 offers excellent reliability and frequency stability as well as guaranteed aging performance. On-chip power supply filtering provides industry-leading power supply noise rejection, simplifying the task of generating low jitter clocks in noisy systems that use switched-mode power supplies. Offered in industry-standard footprints, the Si547 has a dramatically simplified supply chain that enables Silicon Labs to ship custom frequency samples 1-2 weeks after receipt of order. Unlike a traditional XO, where a different crystal is required for each output frequency, the Si547 uses one simple crystal and a DSPLL IC-based approach to provide the desired output frequencies. This process also guarantees 100% electrical testing of every device. The Si547 is factory-configurable for a wide variety of user specifications, including frequency, output format, and OE pin location/polarity. Specific configurations are factory-programmed at time of shipment, eliminating the long lead times associated with custom oscillators.







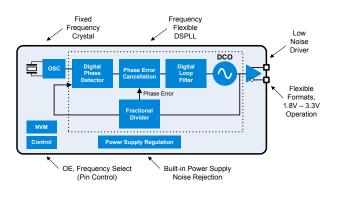
Pin #	Descriptions
1, 2	Selectable via ordering option OE = Output enable; NC = No Connect
3	GND = Ground
4	CLK+ = Clock output
5	CLK- = Complementary clock output. Not used for CMOS.
6	VDD = Power supply
7	FS1 = Frequency Select 1
8	FS0 = Frequency Select 0

#### **KEY FEATURES**

- Available with any four selectable frequencies from 200 kHz to 1500 MHz
- Ultra low jitter: 80 fs Typ RMS (12 kHz – 20 MHz)
- Excellent PSNR and supply noise immunity: -80 dBc Typ
- 7 ppm stability option (-40 to 85C)
- 3.3 V, 2.5 V and 1.8 V V<sub>DD</sub> supply operation from the same part number
- LVPECL, LVDS, CML, HCSL, CMOS, and Dual CMOS output options
- 2.5x3.2, 3.2x5, 5x7 mm package options
- Samples available with 1-2 week lead times

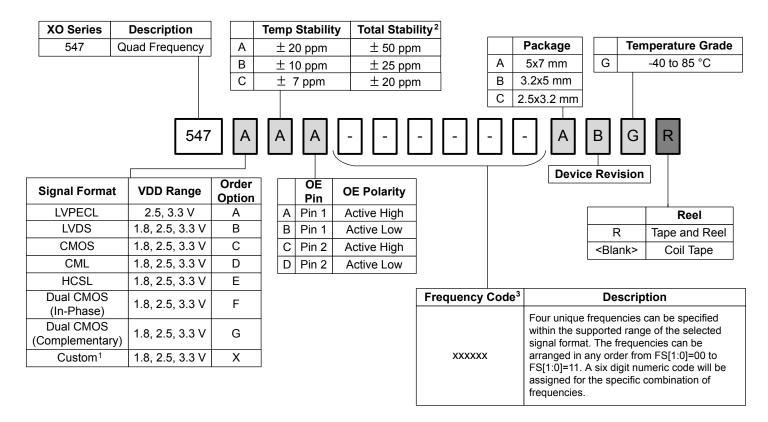
#### APPLICATIONS

- · 100G/200G/400G OTN, coherent optics
- 10G/25G/40G/100G Ethernet
- 3G-SDI/12G-SDI/24G-SDI broadcast video ٠
- Servers, switches, storage, NICs, search acceleration
- Test and measurement
- Clock and data recovery
- FPGA/ASIC clocking



### 1. Ordering Guide

The Si547 XO supports a variety of options including frequency, output format, and OE pin location/polarity, as shown in the chart below. Specific device configurations are programmed into the part at time of shipment, and samples are available in 1-2 weeks. Silicon Laboratories provides an online part number configuration utility to simplify this process. Refer to www.silabs.com/oscillators to access this tool and for further ordering instructions.



#### Notes:

- 1. Contact Silicon Labs for non-standard configurations.
- 2. Total stability includes temp stability, initial accuracy, load pulling, VDD variation, and 20 year aging at 70 °C.
- 3. Create custom part numbers at www.silabs.com/oscillators.

#### 1.1 Technical Support

Frequently Asked Questions (FAQ)	www.silabs.com/Si547-FAQ
Oscillator Phase Noise Lookup Utility	www.silabs.com/oscillator-phase-noise-lookup
Quality and Reliability	www.silabs.com/quality
Development Kits	www.silabs.com/oscillator-tools

### 2. Electrical Specifications

#### Table 2.1. Electrical Specifications

 $V_{DD}$  = 1.8 V, 2.5 or 3.3 V  $\pm$  5%,  $T_A$  = –40 to 85 °C

	Test Condition/Comment	Min	Тур	Max	Unit
T <sub>A</sub>		-40		85	°C
F <sub>CLK</sub>	LVPECL, LVDS, CML	0.2	_	1500	MHz
	HCSL	0.2	_	400	MHz
	CMOS, Dual CMOS	0.2	_	250	MHz
V <sub>DD</sub>	3.3 V	3.135	3.3	3.465	V
	2.5 V	2.375	2.5	2.625	V
	1.8 V	1.71	1.8	1.89	V
I <sub>DD</sub>	LVPECL (output enabled)	_	107	153	mA
	LVDS/CML (output enabled)	_	83	121	mA
	HCSL (output enabled)		86	126	mA
	CMOS (output enabled)	_	87	127	mA
	Dual CMOS (output enabled)	_	92	141	mA
	Tristate Hi-Z (output disabled)	_	73	112	mA
	Frequency stability Grade A	-20		20	ppm
	Frequency stability Grade B	-10		10	ppm
	Frequency stability Grade C	-7	—	7	ppm
F <sub>STAB</sub>	Frequency stability Grade A	-50		50	ppm
	Frequency stability Grade B	-25	—	25	ppm
	Frequency stability Grade C	-20		20	ppm
T <sub>R</sub> /T <sub>F</sub>	LVPECL/LVDS/CML	_	—	350	ps
	CMOS / Dual CMOS (C <sub>L</sub> = 5 pF)	_	0.5	1.5	ns
	HCSL, F <sub>CLK</sub> >50 MHz		_	550	ps
D <sub>C</sub>	All formats	45		55	%
V <sub>IH</sub>		0.7 × V <sub>DD</sub>			V
VIL		_		0.3 × V <sub>DD</sub>	V
T <sub>D</sub>	Output Disable Time, F <sub>CLK</sub> > 10 MHz		_	3	μs
TE	Output Enable Time, F <sub>CLK</sub> > 10 MHz			20	μs
T <sub>FS</sub>	Settling Time after FS Change			10	ms
tosc	Time from 0.9 × V <sub>DD</sub> until output fre- quency (F <sub>CLK</sub> ) within spec	_		10	ms
V <sub>RAMP</sub>	Fastest V <sub>DD</sub> ramp rate allowed on startup	_		9	V/ms
	F <sub>CLK</sub> V <sub>DD</sub> I <sub>DD</sub> F <sub>STAB</sub> T <sub>R</sub> /T <sub>F</sub> D <sub>C</sub> V <sub>IH</sub> V <sub>IL</sub> T <sub>D</sub> T <sub>E</sub> T <sub>FS</sub> tosc	$\begin{tabular}{ c c c c } \hline F_{CLK} & LVPECL, LVDS, CML \\ \hline HCSL \\ \hline CMOS, Dual CMOS \\ \hline V_{DD} & 3.3 V \\ \hline 2.5 V \\ \hline 1.8 V \\ \hline I_{DD} & LVPECL (output enabled) \\ \hline LVDS/CML (output enabled) \\ \hline HCSL (output enabled) \\ \hline HCSL (output enabled) \\ \hline MCSS (output enabled) \\ \hline Dual CMOS (output enabled) \\ \hline Dual CMOS (output enabled) \\ \hline Tristate Hi-Z (output disabled) \\ \hline Tristate Hi-Z (output disabled) \\ \hline Frequency stability Grade A \\ \hline Frequency stability Grade B \\ \hline Frequency stability Grade C \\ \hline F_{STAB} & Frequency stability Grade A \\ \hline Frequency stability Grade B \\ \hline Frequency stability Grade C \\ \hline T_R/T_F & LVPECL/LVDS/CML \\ \hline CMOS / Dual CMOS (C_L = 5 pF) \\ \hline HCSL, F_{CLK} > 50 MHz \\ \hline D_C & All formats \\ \hline V_{IH} & V_{IL} \\ \hline T_D & Output Disable Time, F_{CLK} > 10 MHz \\ \hline T_FS & Settling Time after FS Change \\ \hline t_{OSC} & Time from 0.9 \times V_{DD} until output frequency (F_{CLK}) within spec \\ \hline V_{RAMP} & Fastest V_{DD} ramp rate allowed on \\ \hline \end{tabular}$	$\begin{tabular}{ c c c c } \hline Red {c} & Red {$	$F_{CLK}$ LVPECL, LVDS, CML         0.2            HCSL         0.2            CMOS, Dual CMOS         0.2            VDD         3.3 V         3.135         3.3           2.5 V         2.375         2.5           1.8 V         1.71         1.8           IDD         LVPECL (output enabled)          83           HCSL (output enabled)          83           HCSL (output enabled)          87           Dual CMOS (output enabled)          87           Frequency stability Grade A         -20            Frequency stability Grade B         -10            Frequency stability Grade C         -7            Frequency stability Grade C         -20            TR/TF         LVPECL/LVDS/CML             DC         All formats         45	FGLK         LVPECL, LVDS, CML         0.2         —         1500           HCSL         0.2         —         400           CMOS, Dual CMOS         0.2         —         250           VDD         3.3 V         3.135         3.3         3.465           2.5 V         2.375         2.5         2.625           1.8 V         1.71         1.8         1.89           IDD         LVPECL (output enabled)         —         83         121           HCSL (output enabled)         —         83         121           HCSL (output enabled)         —         86         128           CMOS (output enabled)         —         87         127           Dual CMOS (output enabled)         —         87         112           Tristate Hi-Z (output disabled)         —         92         141           Tristate Hi-Z (output disabled)         —         73         112           Frequency stability Grade A         -20         —         20           Frequency stability Grade C         -7         —         7           Frequency stability Grade C         -20         —         20           TR/TF         LVPECL/LVDS/CML         —         —

Parameter	Symbol	Test Condition/Comment	Min	Тур	Max	Unit
LVPECL Output Option <sup>3</sup>	V <sub>OC</sub>	Mid-level	V <sub>DD</sub> – 1.42	_	V <sub>DD</sub> – 1.25	V
	Vo	Swing (diff)	1.1		1.9	$V_{PP}$
LVDS Output Option <sup>4</sup>	V <sub>OC</sub>	Mid-level (2.5 V, 3.3 V VDD)	1.125	1.20	1.275	V
		Mid-level (1.8 V VDD)	0.8	0.9	1.0	V
	V <sub>O</sub>	Swing (F <sub>CLK</sub> ≤ 1.4 GHz)	0.6	0.7	0.9	$V_{PP}$
		Swing (F <sub>CLK</sub> > 1.4 GHz)	0.5	0.7	0.9	$V_{PP}$
HCSL Output Option <sup>5</sup>	V <sub>OH</sub>	Output voltage high	660	750	850	mV
	V <sub>OL</sub>	Output voltage low	-150	0	150	mV
	V <sub>C</sub>	Crossing voltage	250	350	550	mV
CML Output Option (AC-Coupled)	Vo	Swing (diff)	0.6	0.8	1.0	V <sub>PP</sub>
CMOS Output Option	V <sub>OH</sub>	I <sub>OH</sub> = 8/6/4 mA for 3.3/2.5/1.8 V VDD	0.85 × V <sub>DD</sub>		—	V
	V <sub>OL</sub>	I <sub>OL</sub> = 8/6/4 mA for 3.3/2.5/1.8 V VDD	—		0.15 × V <sub>DD</sub>	V

#### Notes:

1. Total Stability includes temperature stability, initial accuracy, load pulling, VDD variation, and aging for 20 yrs at 70 °C.

2. OE includes a 50 k $\Omega$  pull-up to VDD for OE active high. Includes a 50 k $\Omega$  pull-down to GND for OE active low. FS0 and FS1 pins each include a 50 k $\Omega$  pull-up to VDD. NC (No Connect) pins include a 50 k $\Omega$  pull-down to GND.

3.50  $\Omega$  to  $V_{DD}$  – 2.0 V.

4.  $R_{term}$  = 100  $\Omega$  (differential).

5.50  $\Omega$  to GND.

#### Table 2.2. Clock Output Phase Jitter and PSNR

#### $V_{DD}$ = 1.8 V, 2.5 or 3.3 V $\pm$ 5%, $T_A$ = –40 to 85 °C

Parameter	Symbol	Test Condition/Comment	Min	Тур	Мах	Unit
Phase Jitter (RMS, 12kHz - 20MHz) <sup>1</sup>	фJ	F <sub>CLK</sub> ≥ 200 MHz	_	80	110	fs
3.2 x 5 mm, All Differential Formats		100 MHz ≤ F <sub>CLK</sub> < 200 MHz	_	100	150	fs
		LVPECL @ 156.25 MHz	_	90	125	fs
Phase Jitter (RMS, 12kHz - 20MHz) <sup>1</sup>	фј	F <sub>CLK</sub> ≥ 200 MHz	_	80	130	fs
5 x 7 mm, All Differential Formats		100 MHz ≤ F <sub>CLK</sub> < 200 MHz	_	100	150	fs
		LVPECL @ 156.25 MHz	_	90	125	fs
Phase Jitter (RMS, 12kHz - 20MHz) <sup>1</sup>	фј	F <sub>CLK</sub> ≥ 200 MHz	_	90	130	fs
2.5 x 3.2 mm, All Differential Formats		LVDS @ 625 MHz	_	90	130	fs
		100 MHz ≤ F <sub>CLK</sub> < 200 MHz	_	100	150	fs
Phase Jitter (RMS, 12kHz - 20MHz) <sup>1</sup> CMOS / Dual CMOS Formats	φJ	10 MHz ≤ F <sub>CLK</sub> ≤ 250 MHz	_	200	_	fs
Spurs Induced by External Power Supply	PSNR	100 kHz sine wave	_	-83	_	
Noise, 50 mVpp Ripple. LVDS 156.25 MHz Output		200 kHz sine wave	_	-83	_	dBc
		500 kHz sine wave	_	-82		UDC
		1 MHz sine wave	_	-85	_	

Parameter	Symbol	Test Condition/Comment	Min	Тур	Мах	Unit	
Note:							
1. Guaranteed by characterization. Jitter inclusive of any spurs.							

### Table 2.3. 3 x 2.5 mm Clock Output Phase Noise (Typical, 50 ppm Total Stability Option)

Offset Frequency (f)	156.25 MHz LVDS	200 MHz LVDS	644.53125 MHz LVDS	Unit
100 Hz	-106	-102	-92	
1 kHz	–133	–129	–119	
10 kHz	-140	–138	–127	
100 kHz	-145	-142	–132	dBc/Hz
1 MHz	-152	-150	–139	
10 MHz	–160	-160	-154	
20 MHz	–161	-161	–155	
Offset Frequency (f)	156.25 MHz LVPECL	200 MHz LVPECL	644.53125 MHz LVPECL	Unit
100 Hz	-103	-104	-91	
1 kHz	–130	–128	–118	
10 kHz	-140	–138	–127	
100 kHz	-145	-142	–132	dBc/Hz
1 MHz	-152	-150	-140	
10 MHz	-162	-162	–155	
20 MHz	-163	-163	-156	

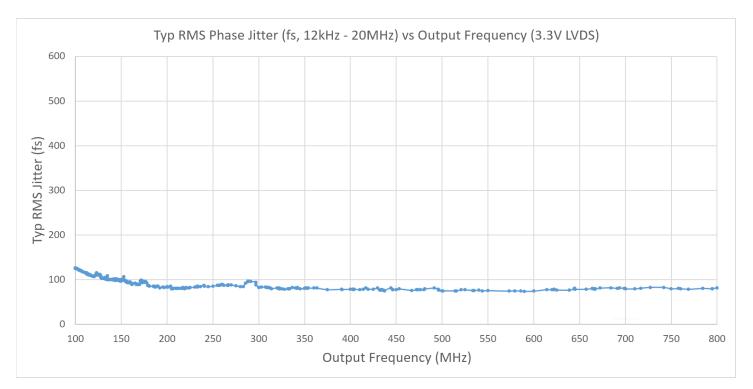


Figure 2.1. Phase Jitter vs. Output Frequency

Phase jitter measured with Agilent E5052 using a differential-to-single ended converter (balun or buffer). Measurements collected for >700 commonly used frequencies. Phase noise plots for specific frequencies are available using our free, online Oscillator Phase Noise Lookup Tool at www.silabs.com/oscillators.

Parameter	Test Condition
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross and Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level (MSL): 3.2 x 5, 5 x 7 packages	1
Moisture Sensitivity Level (MSL): 2.5 x 3.2 package	2
Contact Pads: 3.2x5, 5x7 packages	Au/Ni (0.3 - 1.0 μm / 1.27 - 8.89 μm)
Contact Pads: 2.5x3.2 packages	Au/Pd/Ni (0.03 - 0.12 μm / 0.1 - 0.2 μm / 3.0 - 8.0 μm)
Noto	

Note:

1. For additional product information not listed in the data sheet (e.g. RoHS Certifications, MDDS data, qualification data, REACH Declarations, ECCN codes, etc.), refer to our "Corporate Request For Information" portal found here: www.silabs.com/support/ quality/Pages/RoHSInformation.aspx.

#### Table 2.5. Thermal Conditions

#### Max Junction Temperature = 125 °C

Package	Parameter	Symbol	Test Condition	Value	Uni
	Thermal Resistance Junction to Ambient	Θ <sub>JA</sub>	Still Air, 85 °C	80	°C/V
2.5 x 3.2 mm 8-pin DFN	Thermal Parameter Junction to Board	$\Psi_{JB}$	Still Air, 85 °C	39	°C/V
	Thermal Parameter Junction to Top Center	$\Psi_{JT}$	Still Air, 85 °C	17	°C/V
3.2 × 5 mm 8-pin CLCC	Thermal Resistance Junction to Ambient	Θ <sub>JA</sub>	Still Air, 85 °C	55	°C/V
	Thermal Parameter Junction to Board	$\Psi_{JB}$	Still Air, 85 °C	20	°C/V
	Thermal Parameter Junction to Top Center	$\Psi_{JT}$	Still Air, 85 °C	20	°C/V
	Thermal Resistance Junction to Ambient	Θ <sub>JA</sub>	Still Air, 85 °C	53	°C/V
5 × 7 mm 8-pin CLCC	Thermal Parameter Junction to Board	$\Psi_{JB}$	Still Air, 85 °C	26	°C/V
5 p 5200	Thermal Parameter Junction to Top Center	Ψ <sub>JT</sub>	Still Air, 85 °C	26	°C/V

#### Table 2.6. Absolute Maximum Ratings<sup>1</sup>

Parameter	Symbol	Rating	Unit
Maximum Operating Temp.	T <sub>AMAX</sub>	95	°C
Storage Temperature	T <sub>S</sub>	–55 to 125	°C
Supply Voltage	V <sub>DD</sub>	-0.5 to 3.8	°C
Input Voltage	V <sub>IN</sub>	–0.5 to V <sub>DD</sub> + 0.3	V
ESD HBM (JESD22-A114)	НВМ	2.0	kV
Solder Temperature <sup>2</sup>	T <sub>PEAK</sub>	260	°C
Solder Time at T <sub>PEAK</sub> <sup>2</sup>	T <sub>P</sub>	20–40	sec

Notes:

1. Stresses beyond those listed in this table may cause permanent damage to the device. Functional operation specification compliance is not implied at these conditions. Exposure to maximum rating conditions for extended periods may affect device reliability.

2. The device is compliant with JEDEC J-STD-020.

### 3. Dual CMOS Buffer

Dual CMOS output format ordering options support either complementary or in-phase signals for two identical frequency outputs. This feature enables replacement of multiple XOs with a single Si547 device.

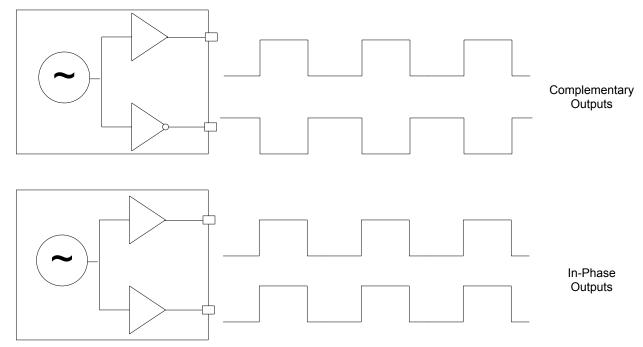


Figure 3.1. Integrated 1:2 CMOS Buffer Supports Complementary or In-Phase Outputs

### 4. Recommended Output Terminations

The output drivers support both AC-coupled and DC-coupled terminations as shown in figures below.

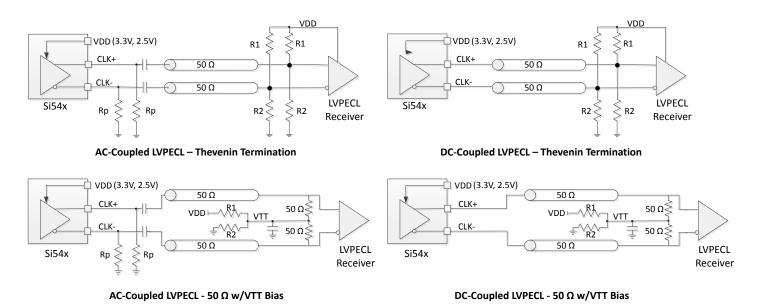
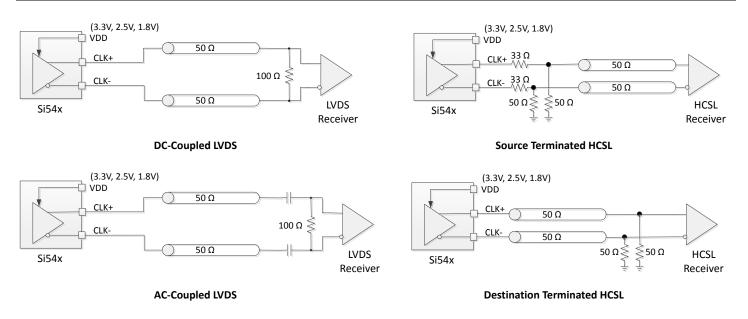


Figure 4.1. LVPECL Output Terminations

		ed LVPECL esistor Values		DC Coupled LVPECL Termination Resistor Values			
VDD	R1	R2	Rp	VDD R1 R2			
3.3 V	127 Ω	82.5 Ω	130 Ω	3.3 V	127 Ω	82.5 Ω	
2.5 V	250 Ω	62.5 Ω	90 Ω	2.5 V	250 Ω	62.5 Ω	





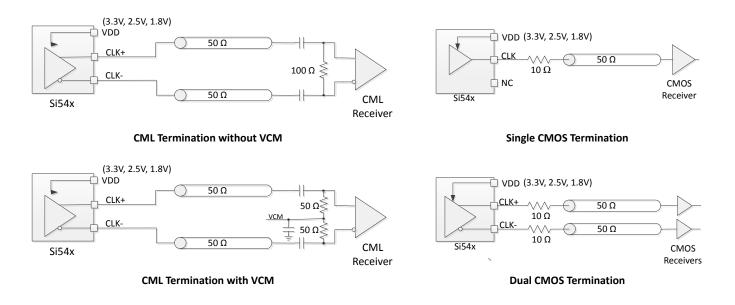
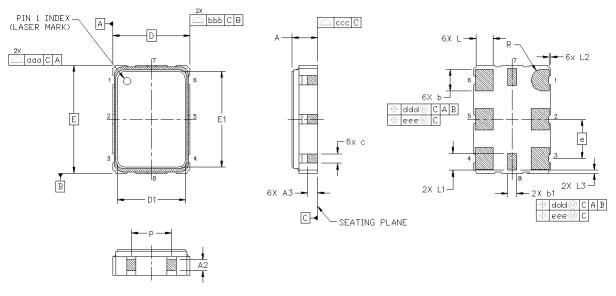


Figure 4.3. CML and CMOS Output Terminations

### 5. Package Outline

#### 5.1 Package Outline (5x7 mm)

The figure below illustrates the package details for the 5x7 mm Si547. The table below lists the values for the dimensions shown in the illustration.



#### Figure 5.1. Si547 (5x7 mm) Outline Diagram

Dimension	Min	Nom	Мах	Dimension	Min	Nom	Max
А	1.07	1.18	1.33	L	1.07	1.17	1.27
A2	0.40	0.50	0.60	L1	1.00	1.10	1.20
A3	0.45	0.55	0.65	L2	0.05	0.10	0.15
b	1.30	1.40	1.50	L3	0.15	0.20	0.25
b1	0.50	0.60	0.70	р	1.70		1.90
С	0.50	0.60	0.70	R	0.70 REF		
D		5.00 BSC		ааа	0.15		
D1	4.30	4.40	4.50	bbb		0.15	
е		2.54 BSC		ссс		0.08	
E	7.00 BSC		ddd		0.10		
E1	6.10 6.20 6.30			eee		0.05	

#### Table 5.1. Package Diagram Dimensions (mm)

#### Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

#### 5.2 Package Outline (3.2x5 mm)

The figure below illustrates the package details for the 3.2x5 mm Si547. The table below lists the values for the dimensions shown in the illustration.

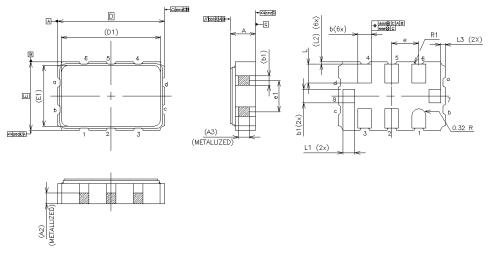


Figure 5.2. Si547 (3.2x5 mm) Outline Diagram

Table 5.2.	Package	Diagram	Dimensions	(mm)
------------	---------	---------	------------	------

Dimension	MIN	NOM	MAX	Dimension	MIN	NOM	MAX
A	1.02	1.17	1.33	E1		2.85 BSC	
A2	0.50	0.55	0.60	L	0.8	0.9	1.0
A3	0.45	0.50	0.55	L1	0.45	0.55	0.65
b	0.54	0.64	0.74	L2	0.05	0.10	0.15
b1	0.54	0.64	0.75	L3	0.15	0.20	0.25
D		5.00 BSC		aaa	0.15		
D1		4.65 BSC		bbb	0.15		
е		1.27 BSC		ссс		0.08	
e1	1.625 TYP			ddd	0.10		
E	3.20 BSC			eee		0.05	
Notes:					1		

1. All dimensions shown are in millimeters (mm) unless otherwise noted.

2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

#### 5.3 Package Outline (2.5x3.2 mm)

The figure below illustrates the package details for the 2.5x3.2 mm Si547. The table below lists the values for the dimensions shown in the illustration.

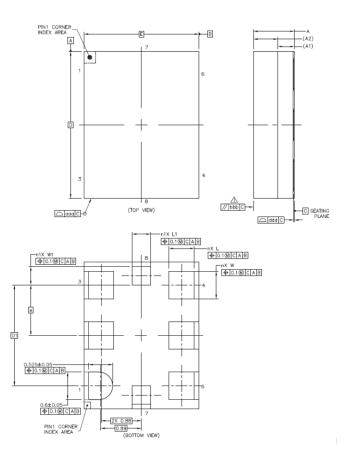


Figure 5.3. Si547 (2.5x3.2 mm) Outline Diagram

Dimension	MIN	NOM	MAX	Dimension	MIN	NOM	MAX
A	—	—	1	L1	0.35	0.4	0.45
A1	0.36 REF			е	1.1 BSC		
A2	0.53 REF			n	5		
D	3.2 BSC			n1	2		
E	2.5 BSC			D1		2.2 BSC	
W	0.55	0.55 0.6 0.65		aaa		0.10	
L	0.5	0.55	0.6	bbb		0.10	
W1	0.35	0.4	0.45	ddd		0.08	

#### Table 5.3. Package Diagram Dimensions (mm)

#### Notes:

1. The dimensions in parentheses are reference.

2. All dimensions shown are in millimeters (mm) unless otherwise noted.

3. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

### 6. PCB Land Pattern

### 6.1 PCB Land Pattern (5x7 mm)

The figure below illustrates the 5x7 mm PCB land pattern for the Si547. The table below lists the values for the dimensions shown in the illustration.

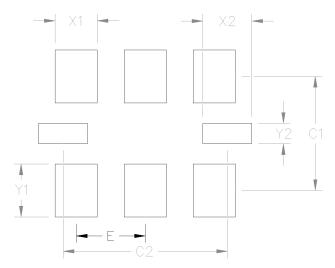


Figure 6.1. Si547 (5x7 mm) PCB Land Pattern

Table 6.1.	PCB Land	Pattern	Dimensions	(mm)
------------	----------	---------	------------	------

Dimension	(mm)	Dimension	(mm)
C1	4.20	Y1	1.95
C2	6.05	X2	1.80
E	2.54	Y2	0.75
X1	1.55		

Notes:

#### General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

#### Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

#### Stencil Design

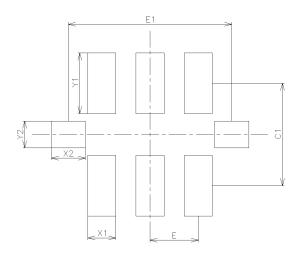
- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1.

#### Card Assembly

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

#### 6.2 PCB Land Pattern (3.2x5 mm)

The figure below illustrates the 3.2x5.0 mm PCB land pattern for the Si547. The table below lists the values for the dimensions shown in the illustration.





#### Table 6.2. PCB Land Pattern Dimensions (mm)

Dimension	(mm)	Dimension	(mm)
C1	2.70	X2	0.90
E	1.27	¥1	1.60
E1	4.30	Y2	0.70
X1	0.74		

#### Notes:

#### General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

#### Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

#### Stencil Design

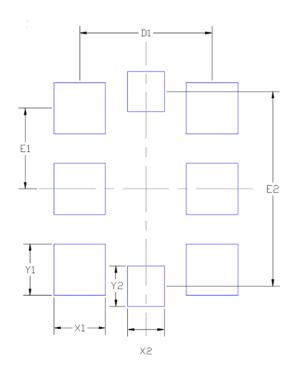
- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 1:1.

#### **Card Assembly**

- 1. A No-Clean, Type-3 solder paste is recommended.
- 2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

#### 6.3 PCB Land Pattern (2.5x3.2 mm)

The figure below illustrates the 2.5x3.2 mm PCB land pattern for the Si547. The table below lists the values for the dimensions shown in the illustration.



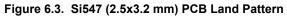


Table 6.3.	PCB Land	Pattern	Dimensions	(mm)
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Dimension	Description	Value (mm)
X1	Width - leads on long sides	0.7
Y1	Height - leads on long sides	0.7
X2	Width - single leads on short sides	0.5
Y2	Height - single leads on short sides	0.55
D1	Pitch in X directions of XL, Y1 leads	1.80
E1	Lead pitch X1, Y1 leads	1.10
E2	Lead pitch X2,Y2 leads	2.65

#### Si547 Data Sheet PCB Land Pattern

Dimension

Description

### Notes:

#### General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

#### Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

#### **Stencil Design**

- 1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 2. The stencil thickness should be 0.125 mm (5 mils).
- 3. The ratio of stencil aperture to land pad size should be 0.8:1 for the pads.

#### Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.

2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

### 7. Top Marking

### 7.1 Top Marking (5x7 and 3.2x5 Packages)

The figure below illustrates the mark specification for the Si547 5x7 and 3.2x5 package sizes. The table below lists the line information.

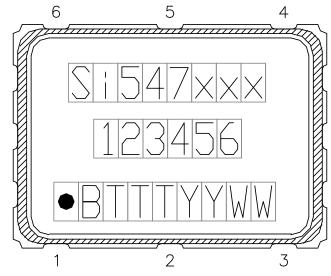


Figure 7.1. Mark Specification

Table 7.1.	Si547	Top Mark	Description
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Line	Position	Description
1	1–8	"Si547", xxx = Ordering Option 1, Option 2, Option 3 (e.g. Si547AAA)
2	1–6	Frequency Code (6-digit custom code as described in the Ordering Guide)
3		Trace Code
	Position 1	Pin 1 orientation mark (dot)
	Position 2	Product Revision (B)
	Position 3–5	Tiny Trace Code (3 alphanumeric characters per assembly release instructions)
	Position 6–7	Year (last two digits of the year), to be assigned by assembly site (ex: 2017 = 17)
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site

#### 7.2 Top Marking (2.5x3.2 Package)

The figure below illustrates the mark specification for the Si547 2.5x3.2 package size. The table below lists the line information.

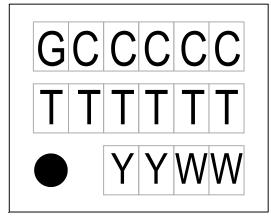


Figure 7.2. Mark Specification

#### Table 7.2. Si547 Top Mark Description

Line	Position	Description			
1	1–6	G = Si547, CCCCC = Custom Mark Code			
2	Trace Code				
	1–6	6 digit trace code per assembly release instructions			
3	Position 1	Pin 1 orientation mark (dot)			
	Position 2–3	Year (last two digits of the year), to be assigned by assembly site (ex: 2017 = 17)			
	Position 4–5	Calendar Work Week number (1–53), to be assigned by assembly site			

### 8. Revision History

### **Revision 1.2**

September, 2020

- Added 2.5x3.2 mm package option.
- Updated Table 2.2, Powerup VDD Ramp Rate and LVDS Swing

#### **Revision 1.0**

August, 2018

Added 20 ppm total stability option.

### **Revision 0.75**

March, 2018

Added 25 ppm total stability option.

#### **Revision 0.71**

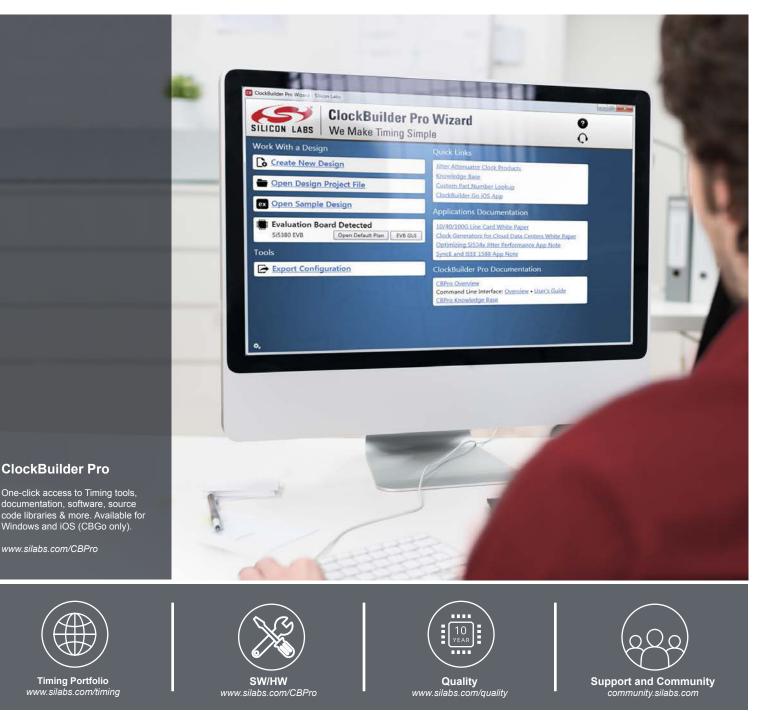
December 11, 2017

• Added 5x7 package and land pattern.

#### **Revision 0.7**

June 27, 2017

· Initial release.



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